

This Swissbit module is an industry standard 240-pin 8-byte DDR3 SDRAM Dual-In-line Memory Module (UDIMM) which is organized as x72 high speed CMOS memory arrays. The module uses internally configured octal-bank DDR3 SDRAM devices. The module uses double data rate architecture to achieve high-speed operation. DDR3 SDRAM modules operate from a differential clock (CK and CK#). READ and WRITE accesses to a DDR3 SDRAM module is burst-oriented; accesses start at a selected location and continue for a programmed number of locations in a programmed sequence. The burst length is either four or eight locations. An auto precharge function can be enabled to provide a self-timed row precharge that is initiated at the end of a burst access. The DDR3 SDRAM devices have a multibank architecture which allows a concurrent operation that is providing a high effective bandwidth. A self refresh mode is provided and a power-saving "power-down" mode. All inputs and all full drive-strength outputs are SSTL_15 compatible.

The DDR3 SDRAM module uses the serial presence detect (SPD) function implemented via serial EEPROM using the standard I²C protocol. This nonvolatile storage device contains 256 bytes. The first 128 bytes are utilized by the DIMM manufacturer (Swissbit) to identify the module type, the module's organization and several timing parameters. The second 128 bytes are available to the end user.

Module Configuration

Organization	DDR3 SDRAMs used	Row Addr.	Device Bank Addr.	Column Addr.	Refresh	Module Bank Select
256M x 72bit	18 x 128M x 8bit (1024Mbit)	14	BA0, BA1, BA2	10	8k	S0#, S1#

Module Dimensions

in mm

133.35 (long) x 17.75 (high) x 4.00 [max] (thickness)

Timing Parameters

Part Number	Module Density	Transfer Rate	Clock Cycle/Data bit rate	Latency
SGU02G72H1BG2SA-BBRT	2048 MB	8.5 GB/s	1.87ns/1066MT/s	7-7-7
SGU02G72H1BG2SA-CCRT	2048 MB	10.6 GB/s	1.5ns/1333MT/s	9-9-9

Pin Name

A0 – A9, A11, A13	Address Inputs
A10/AP	Address Input / Autoprecharge Bit
A12/BC#	Address Input / Burst chop
BA0 – BA2	Bank Address Inputs
DQ0 – DQ63	Data Input / Output
CB0 – CB7	ECC check bits
DM0 – DM8	Input Data Mask
DQS0 – DQS8	Data Strobe, positive line
DQS0# - DQS8#	Data Strobe, negative line (only used when differential data strobe mode is enabled)
RAS#	Row Address Strobe
CAS#	Column Address Strobe
WE#	Write Enable
CKE0 – CKE1	Clock Enable
S0#, S1#	Chip Select
CK0 – CK1	Clock Inputs, positive line

CK0# - CK1#	Clock Inputs, negative line
Event#	Temperature event: The EVENT# pin is asserted by the temperature sensor when critical
V _{DD}	Supply Voltage (1.5V± 0.075V)
V _{REFDQ}	Reference voltage: DQ, DM (V _{DD} /2)
V _{REFCA}	Reference voltage: Control, command, and address (V _{DD} /2)
V _{SS}	Ground
V _{TT}	Termination voltage: Used for control, command, and address (V _{DD} /2).
V _{DDSPD}	Serial EEPROM Positive Power Supply
SCL	Serial Clock for Presence Detect
SDA	Serial Data Out for Presence Detect
SA0 – SA2	Presence Detect Address Inputs
ODT0, ODT1	On-Die Termination
NC	No Connection

Pin Configuration

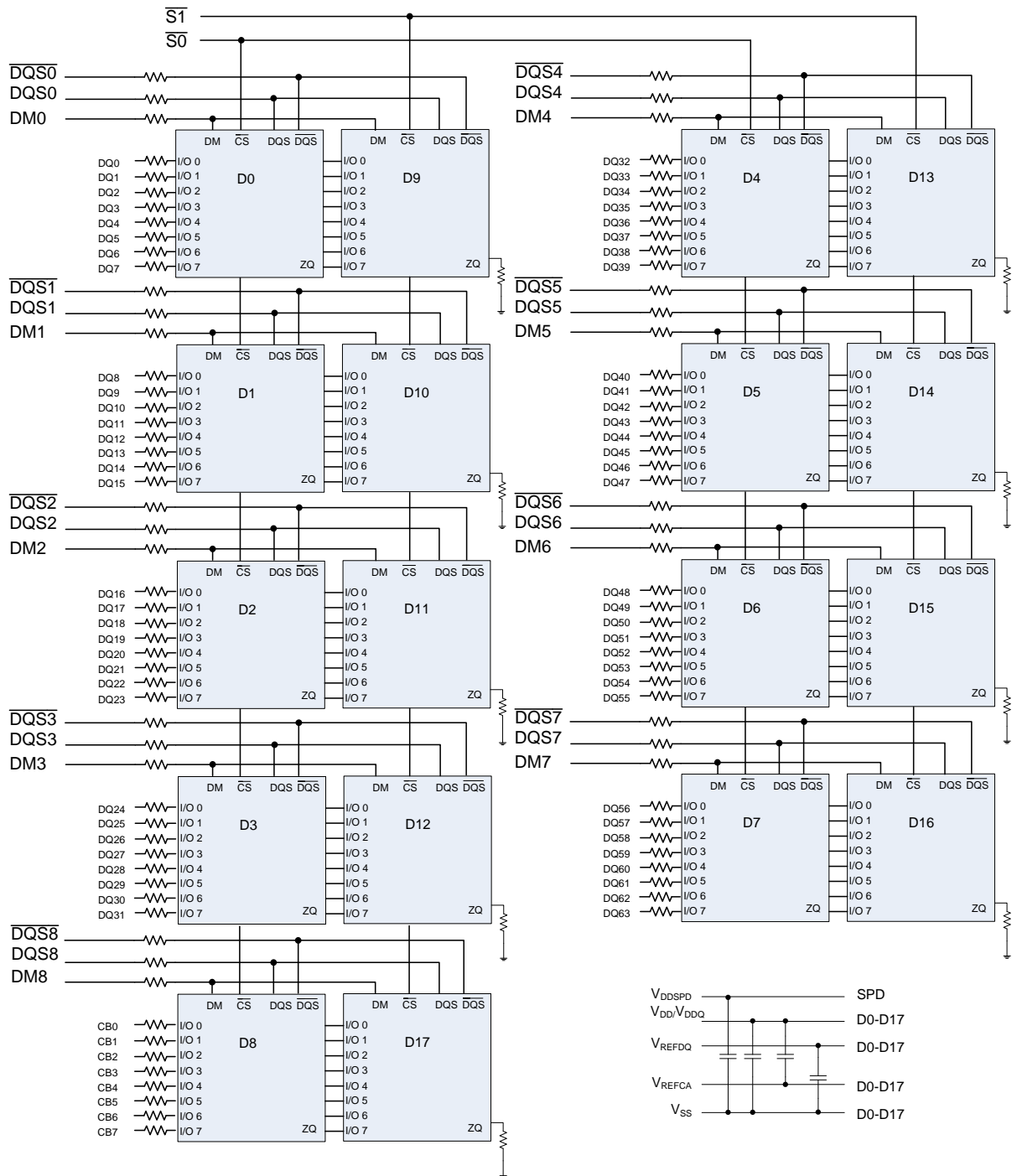
Frontside									
PIN	Symbol	PIN	Symbol	PIN	Symbol	PIN	Symbol	PIN	Symbol
1	V _{REFDQ}	27	DQ18	49	NC	75	V _{DD}	101	V _{SS}
2	V _{SS}	28	DQ19	50	CKE0	76	S1#	102	DQS6#
3	DQ0	29	V _{SS}	51	V _{DD}	77	ODT1	103	DQS6
4	DQ1	30	DQ24	52	BA2	78	V _{DD}	104	V _{SS}
5	V _{SS}	31	DQ25	53	NC(Err_Out#)	79	NC(S2#)	105	DQ50
6	DQS0#	32	V _{SS}	54	V _{DD}	80	V _{SS}	106	DQ51
7	DQS0	33	DQS3#	55	A11	81	DQ32	107	V _{SS}
8	V _{SS}	34	DQS3	56	A7	82	DQ33	108	DQ56
9	DQ2	35	V _{SS}	57	V _{DD}	83	V _{SS}	109	DQ57
10	DQ3	36	DQ26	58	A5	84	DQS4#	110	V _{SS}
11	V _{SS}	37	DQ27	59	A4	85	DQS4	111	DQS7#
12	DQ8	38	V _{SS}	60	V _{DD}	86	V _{SS}	112	DQS7
13	DQ9	39	CB0	61	A2	87	DQ34	113	V _{SS}
14	V _{SS}	40	CB1	62	V _{DD}	88	DQ35	114	DQ58
15	DQS1#	41	V _{SS}	63	CK1	89	V _{SS}	115	DQ59
16	DQS1	42	DQS8#	64	CK1#	90	DQ40	116	V _{SS}
17	V _{SS}	43	DQS8	65	V _{DD}	91	DQ41	117	SA0
18	DQ10	44	V _{SS}	66	V _{DD}	92	V _{SS}	118	SCL
19	DQ11	45	CB2	67	V _{REFCA}	93	DQS5#	119	SA2
20	V _{SS}	46	CB3	68	NC(Par_In)	94	DQS5	120	V _{TT}
21	DQ16	47	V _{SS}	69	V _{DD}	95	V _{SS}		
22	DQ17	48	NC	70	A10/ AP	96	DQ42		
23	V _{SS}			71	BA0	97	DQ43		
24	DQS2#			72	V _{DD}	98	V _{SS}		
25	DQS2			73	WE#	99	DQ48		
26	V _{SS}			74	CAS#	100	DQ49		

Signals in brackets (...) may be connected at the DIMM socket, but are not used on the DIMM

Backside									
PIN	Symbol	PIN	Symbol	PIN	Symbol	PIN	Symbol	PIN	Symbol
121	V _{SS}	147	DQ23	169	CKE1	195	ODT0	221	DM6(DQS15)
122	DQ4	148	V _{SS}	170	V _{DD}	196	A13	222	NC(DQS15#)
123	DQ5	149	DQ28	171	NC(A15)	197	V _{DD}	223	V _{SS}
124	V _{SS}	150	DQ29	172	NC(A14)	198	NC(S3#)	224	DQ54
125	DM0(DQS9)	151	V _{SS}	173	V _{DD}	199	V _{SS}	225	DQ55
126	NC(DQS9#)	152	DM3(DQS12)	174	A12, BC#	200	DQ36	226	V _{SS}
127	V _{SS}	153	NC(DQS12#)	175	A9	201	DQ37	227	DQ60
128	DQ6	154	V _{SS}	176	V _{DD}	202	V _{SS}	228	DQ61
129	DQ7	155	DQ30	177	A8	203	DM4(DQS13)	229	V _{SS}
130	V _{SS}	156	DQ31	178	A6	204	NC(DQS13#)	230	DM7(DQS16)
131	DQ12	157	V _{SS}	179	V _{DD}	205	V _{SS}	231	NC(DQS16#)
132	DQ13	158	CB4	180	A3	206	DQ38	232	V _{SS}
133	V _{SS}	159	CB5	181	A1	207	DQ39	233	DQ62
134	DM1(DQS10)	160	V _{SS}	182	V _{DD}	208	V _{SS}	234	DQ63
135	NC(DQS10#)	161	DM8(DQS17)	183	V _{DD}	209	DQ44	235	V _{SS}
136	V _{SS}	162	NC(DQS17#)	184	CK0	210	DQ45	236	V _{DDSPD}
137	DQ14	163	V _{SS}	185	CK0#	211	V _{SS}	237	SA1
138	DQ15	164	CB6	186	V _{DD}	212	DM5(DQS14)	238	SDA
139	V _{SS}	165	CB7	187	NC(EVENT#)	213	NC(DQS14#)	239	V _{SS}
140	DQ20	166	V _{SS}	188	A0	214	V _{SS}	240	V _{TT}
141	DQ21	167	NC(TEST)	189	V _{DD}	215	DQ46		
142	V _{SS}	168	RESET#	190	BA1	216	DQ47		
143	DM2(DQS11)			191	V _{DD}	217	V _{SS}		
144	NC(DQS11#)			192	RAS#	218	DQ52		
145	V _{SS}			193	S0#	219	DQ53		
146	DQ22			194	V _{DD}	220	V _{SS}		

Signals in brackets (...) may be connected at the DIMM socket, but are not used on the DIMM

**FUNCTIONAL BLOCK DIAGRAM 2048MB DDR3 SDRAM DIMM,
2 RANKS AND 18 COMPONENTS**



- BA0-BA2 → BA0-BA2: SDRAM D0-D17
- A0-A13 → A0-A13: SDRAM D0-D17
- RAS → RAS: SDRAM D0-D17
- CAS → CAS: SDRAM D0-D17
- WE → WE: SDRAM D0-D17
- ODT0 → ODT: SDRAM D0-D8
- ODT1 → ODT: SDRAM D9-D17
- CKE0 → CKE: SDRAM D0-D8
- CKE1 → CKE: SDRAM D9-D17
- CK0,CK1 → CK: SDRAM D0-D17
- CK0,CK1 → CK: SDRAM D0-D17
- RESET → RESET: SDRAM D0-D17

Notes:

1. DQ-to-I/O wiring is shown as recommended but may be changed.
2. DQ/DQS/DQS/ODT/DM/CKE/S relationship must be maintained as shown.
3. DQ, DM, DQS/DQS resistors: Refer to associated topology diagram.
4. Refer to the appropriate clock wiring topology under the DIMM wiring details section of the JEDED document.
5. For each DRAM, a unique ZQ resistor is connected to GND. The ZQ resistor is 240Ω±1%.
6. Refer to associated figure for SPD details.

MAXIMUM ELECTRICAL DC CHARACTERISTICS

PARAMETER/ CONDITION	SYMBOL	MIN	MAX	UNITS
Supply Voltage	V_{DD}	-0.4	1.975	V
I/O Supply Voltage	V_{DDQ}	-0.4	1.975	V
V_{DDL} Supply Voltage	V_{DDL}	-0.4	1.975	V
Voltage on any pin relative to V_{SS}	V_{IN}, V_{OUT}	-0.4	1.975	V
INPUT LEAKAGE CURRENT Any input $0V \leq V_{IN} \leq V_{DD}$, V_{REF} pin $0V \leq V_{IN} \leq 0.95V$ (All other pins not under test = 0V)	I_I			μA
Command/Address RAS#, CAS#, WE#, S#, CKE		-16	16	
CK, CK#		-16	16	
DM		-2	2	
OUTPUT LEAKAGE CURRENT (DQ's and ODT are disabled; $0V \leq V_{OUT} \leq V_{DDQ}$)	I_{OZ}	-5	5	μA
DQ, DQS, DQS#				
V_{REF} LEAKAGE CURRENT ; V_{REF} is on a valid level	I_{VREF}	-8	8	μA

DC OPERATING CONDITIONS

PARAMETER/ CONDITION	SYMBOL	MIN	NOM	MAX	UNITS
Supply Voltage	V_{DD}	1.425	1.5	1.575	V
I/O Supply Voltage	V_{DDQ}	1.425	1.5	1.575	V
V_{DDL} Supply Voltage	V_{DDL}	1.425	1.5	1.575	V
I/O Reference Voltage	V_{REF}	$0.49 \times V_{DDQ}$	$0.50 \times V_{DDQ}$	$0.51 \times V_{DDQ}$	V
I/O Termination Voltage (system)	V_{TT}	$0.49 \times V_{DDQ} - 20mV$	$0.50 \times V_{DDQ}$	$0.51 \times V_{DDQ} + 20mV$	V
Input High (Logic 1) Voltage	$V_{IH(DC)}$	$V_{REF} + 0.1$		$V_{DDQ} + 0.3$	V
Input Low (Logic 0) Voltage	$V_{IL(DC)}$	-0.3		$V_{REF} - 0.1$	V

AC INPUT OPERATING CONDITIONS

PARAMETER/ CONDITION	SYMBOL	MIN	MAX	UNITS
Input High (Logic 1) Voltage	$V_{IH(AC)}$	$V_{REF} + 0.175$	-	V
Input Low (Logic 0) Voltage	$V_{IL(AC)}$	-	$V_{REF} - 0.175$	V

CAPACITANCE

At DDR3 data rates, it is recommended to simulate the performance of the module to achieve optimum values. When inductance and delay parameters associated with trace lengths are used in simulations, they are significantly more accurate and realistic than a gross estimation of module capacitance. Simulations can then render a considerably more accurate result. JEDEC modules are now designed by using simulations to close timing budgets.

I_{DD} Specifications and Conditions(0°C ≤ T_{CASE} ≤ +85°C; V_{DDQ} = +1.5V ± 0.075V, V_{DD} = +1.5V ± 0.075V)

Parameter & Test Condition	Symbol	max.		Unit
		10600-999	8500-777	
OPERATING CURRENT *) : One device bank Active-Precharge; t _{RC} = t _{RC} (I _{DD}); t _{CK} = t _{CK} (I _{DD}); CKE is HIGH, CS# is HIGH between valid commands; DQ inputs changing once per clock cycle; Address and control inputs changing once every two clock cycles	I _{DD0}	405	405	mA
OPERATING CURRENT *) : One device bank; Active-Read-Precharge; I _{OUT} = 0mA; BL = 4, CL = CL (I _{DD}), AL = 0; t _{CK} = t _{CK} (I _{DD}), t _{RC} = t _{RC} (I _{DD}), t _{RAS} = t _{RAS} MIN (I _{DD}), t _{RCD} = t _{RCD} (I _{DD}); CKE is HIGH, CS# is HIGH between valid commands; Address inputs changing once every two clock cycles; Data Pattern is same as I _{DD4W}	I _{DD1}	468	450	mA
PRECHARGE POWER-DOWN CURRENT: All device banks idle; Power-down mode; t _{CK} = t _{CK} (I _{DD}); CKE is LOW; All Control and Address bus inputs are not changing; DQ's are floating at V _{REF}	Fast Exit	I _{DD2P}	216	mA
	Slow Exit		180	
PRECHARGE QUIET STANDBY CURRENT: All device banks idle; t _{CK} = t _{CK} (I _{DD}); CKE is HIGH, CS# is HIGH; All Control and Address bus inputs are not changing; DQ's are floating at V _{REF}	I _{DD2Q}	270	270	mA
PRECHARGE STANDBY CURRENT: All device banks idle; t _{CK} = t _{CK} (I _{DD}); CKE is HIGH, CS# is HIGH; All other Control and Address bus inputs are changing once every two clock cycles; DQ inputs changing once per clock cycle	I _{DD2N}	270	270	mA
ACTIVE POWER-DOWN CURRENT: All device banks open; t _{CK} = t _{CK} (I _{DD}); CKE is LOW; All Control and Address bus inputs are not changing; DQ's are floating at V _{REF} (always fast exit)	I _{DD3P}	270	270	mA
ACTIVE STANDBY CURRENT: All device banks open; t _{CK} = t _{CK} (I _{DD}), t _{RAS} = t _{RAS} MAX (I _{DD}), t _{RP} = t _{RP} (I _{DD}); CKE is HIGH, CS# is HIGH between valid commands; All other Control and Address bus inputs are changing once every two clock cycles; DQ inputs changing once per clock cycle	I _{DD3N}	360	360	mA
OPERATING READ CURRENT: All device banks open, Continuous burst reads; One module rank active; I _{OUT} = 0mA; BL = 4, CL = CL (I _{DD}), AL = 0; t _{CK} = t _{CK} (I _{DD}), t _{RAS} = t _{RAS} MAX (I _{DD}), t _{RP} = t _{RP} (I _{DD}); CKE is HIGH, CS# is HIGH between valid commands; Address bus inputs are changing once every two clock cycles; DQ inputs changing once per clock cycle	I _{DD4R}	720	630	mA

Parameter & Test Condition	Symbol	max.		Unit
		10600-999	8500-777	
OPERATING WRITE CURRENT: All device banks open, Continuous burst writes; One module rank active; BL = 4, CL = CL (I _{DD}), AL = 0; t _{CK} = t _{CK} (I _{DD}), t _{RAS} = t _{RAS} MAX (I _{DD}), t _{RP} = t _{RP} (I _{DD}); CKE is HIGH, CS# is HIGH between valid commands; Address bus inputs are changing once every two clock cycles; DQ inputs changing once per clock cycle	I _{DD4W}	720	630	mA
BURST REFRESH CURRENT: t _{CK} = t _{CK} (I _{DD}); refresh command at every t _{RFC} (I _{DD}) interval, CKE is HIGH, CS# is HIGH between valid commands; All other Control and Address bus inputs are changing once every two clock cycles; DQ inputs changing once per clock cycle	I _{DD5}	1620	1530	mA
SELF REFRESH CURRENT: CK and CK# at 0V; CKE ≤ 0.2V; All other Control and Address bus inputs are floating at V _{REF} ; DQ's are floating at V _{REF}	I _{DD6}	180	180	mA
OPERATING CURRENT*) : Four device bank interleaving READs, I _{OUT} = 0mA; BL = 4, CL = CL (I _{DD}), AL = t _{RCD} (I _{DD}) - 1 x t _{CK} (I _{DD}); t _{CK} = t _{CK} (I _{DD}), t _{RC} = t _{RC} (I _{DD}), t _{RRD} = t _{RRD} (I _{DD}), t _{RCD} = t _{RCD} (I _{DD}); CKE is HIGH, CS# is HIGH between valid commands; Address bus inputs are not changing during DESELECT; DQ inputs changing once per clock cycle	I _{DD7}	1260	1035	mA

*) Value calculated as one module rank in this operating condition, and all other module ranks in IDD2P (CKE LOW) mode.

TIMING VALUES USED FOR I_{DD} MEASUREMENT

I _{DD} MEASUREMENT CONDITIONS			
SYMBOL	10600-999	8500-777	Unit
CL (I _{DD})	9	7	t _{CK}
t _{RCD} (I _{DD})	13.5	13.125	ns
t _{RC} (I _{DD})	49.5	50.625	ns
t _{RRD} (I _{DD})	6	7.5	ns
t _{CK} (I _{DD})	1.5	1.87	ns
t _{RAS} MIN (I _{DD})	36	37.5	ns
t _{RAS} MAX (I _{DD})	70'200	70'200	ns
t _{RP} (I _{DD})	13.5	13.125	ns
t _{RFC} (I _{DD})	110	110	ns

DDR3 SDRAM COMPONENT ELECTRICAL CHARACTERISTICS AND RECOMMENDED AC OPERATING CONDITIONS

 (0°C ≤ T_{CASE} ≤ +85°C; V_{DDQ} = +1.5V ± 0.075V, V_{DD} = +1.5V ± 0.075V)

AC CHARACTERISTICS			10600-999		8500-777		
PARAMETER		SYMBOL	MIN	MAX	Min	MAX	Unit
Clock cycle time	CL = 10	t _{CK} (10)	1.5	<1.875	-	-	ns
	CL = 9	t _{CK} (9)	1.5	<1.875	-	-	ns
	CL = 8	t _{CK} (8)	1.875	<2.5	-	-	ns
	CL = 7	t _{CK} (7)	1.875	<2.5	1.875	<2.5	ns
	CL = 6	t _{CK} (6)	2.5	3.3	2.5	3.3	ns
CK high-level width		t _{CH} (avg)	0.47	0.53	0.47	0.53	t _{CK}
CK low-level width		t _{CL} (avg)	0.47	0.53	0.47	0.53	t _{CK}
Data-out high-impedance window from CK/CK#		t _{HZ}		250		300	ps
Data-out low-impedance window from CK/CK#		t _{LZ}	-500	250	-600	300	ps
DQ and DM input setup time relative to DQS		t _{DS(Base)}	30		25		ps
DQ and DM input hold time relative to DQS		t _{DH(Base)}	65		100		ps
DQ and DM input setup time relative to DQS V _{REF} =1V/ns		t _{DS1V}	180		200		ps
DQ and DM input hold time relative to DQS V _{REF} =1V/ns		t _{DH1V}	165		200		ps
DQ and DM input pulse width (for each input)		t _{DIPW}	400		490		ps
DQS, DQS# to DQ skew, per access		t _{DQSQ}		125		150	ps
DQ-DQS hold, DQS to first DQ to go non-valid, per access		t _{QH}	0.38		0.38		t _{CK} (AVG)
DQS input high pulse width		t _{DQSH}	0.45	0.55	0.45	0.55	t _{CK}
DQS input low pulse width		t _{DQSL}	0.45	0.55	0.45	0.55	t _{CK}
DQS, DQS# rising to/from CK, CK#		t _{DQSCK}	-255	255	-300	300	ps
DQS, DQS# rising to/from CK, CK# when DLL disabled		t _{DQSCK} DLL DIS	1	10	1	10	ns
DQS falling edge to CK rising - setup time		t _{DSS}	0.2		0.2		t _{CK}
DQS falling edge from CK rising - hold time		t _{DSH}	0.2		0.2		t _{CK}
DQS read preamble		t _{RPRE}	0.9	Note1	0.9	Note1	t _{CK}
DQS read postamble		t _{RPST}	0.3	Note2	0.3	Note2	t _{CK}
DQS write preamble		t _{WPRE}	0.9		0.9		t _{CK}
DQS write postamble		t _{WPST}	0.3		0.3		t _{CK}
Positive DQS latching edge to associated clock edge		t _{DQSS}	- 0.25	+ 0.25	- 0.25	+ 0.25	t _{CK}
Address and control input pulse width (for each input)		t _{IPW}	620		780		ps
CTRL, CMD, Addr setup to CK, CK#		t _{IS(Base)}	65		125		ps
CTRL, CMD, Addr setup to CK, CK# V _{REF} @ 1V/ns		t _{IS(1V)}	240		300		ps

- 1 The maximum preamble is bound by t_{LZDQS} (MAX)
- 2 The maximum postamble is bound by t_{HZDQS} (MAX)

DDR3 SDRAM COMPONENT ELECTRICAL CHARACTERISTICS AND RECOMMENDED AC OPERATING CONDITIONS (Continued)
 $(0^{\circ}\text{C} \leq T_{\text{CASE}} \leq +85^{\circ}\text{C}; V_{\text{DDQ}} = +1.5\text{V} \pm 0.075\text{V}, V_{\text{DD}} = +1.5\text{V} \pm 0.075\text{V})$

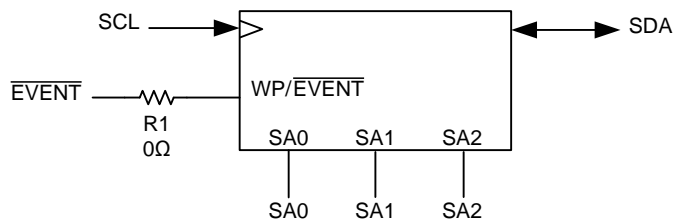
AC CHARACTERISTICS		10600-999		8500-777		Unit
PARAMETER	SYMBOL	MIN	MAX	MIN	MAX	
CTRL, CMD, Addr hold to CK, CK#	$t_{\text{H(Base)}}$	140		200		ps
CTRL, CMD, Addr hold to CK, CK# $V_{\text{REF}} @ 1\text{V/ns}$	$t_{\text{H(1V)}}$	240		300		ps
CAS# to CAS# command delay	t_{CCD}	4		4		t_{CK}
ACTIVE to ACTIVE (same bank) command period	t_{RC}	49.5		50.625		ns
ACTIVE bank a to ACTIVE bank b command	t_{RRD}	max 4nCK,10ns		max 4nCK,7.5ns		ns
ACTIVE to READ or WRITE delay	t_{RCD}	13.5		13.125		ns
Four bank Activate period	t_{FAW}	1K Page size	30		37.5	ns
		2K Page size	45		50	
ACTIVE to PRECHARGE command	t_{RAS}	36	70'200	37.5	70'200	ns
Internal READ to precharge command delay	t_{RTP}	max 4nCK,7.5ns		max 4nCK,7.5ns		ns
Write recovery time	t_{WR}	15		15		ns
Auto precharge write recovery + precharge time	t_{DAL}	$t_{\text{WR}} + t_{\text{RP}}/t_{\text{CK}}$		$t_{\text{WR}} + t_{\text{RP}}/t_{\text{CK}}$		ns
Internal WRITE to READ command delay	t_{WTR}	max 4nCK,7.5ns		max 4nCK,7.5ns		ns
PRECHARGE command period	t_{RP}	13.5		13.125		ns
LOAD MODE command cycle time	t_{MRD}	4		4		t_{CK}
REFRESH to ACTIVE or REFRESH to REFRESH command interval	t_{RFC}	110	70'200	110	70'200	ns
Average periodic refresh interval $0^{\circ}\text{C} \leq T_{\text{CASE}} \leq 85^{\circ}\text{C}$	t_{REFI}		7.8		7.8	μs
	$t_{\text{REFI (IT)}}$		3.9		3.9	
RTT turn-on from ODTL on reference	t_{AON}	-250	250	-300	300	ps
RTT turn-on from ODTL off reference	t_{AOF}	0.3	0.7	0.3	0.7	t_{CK}
Asynchronous RTT turn-on delay (power Down with DLL off)	t_{AONPD}	2	8,5	2	8,5	ns
Asynchronous RTT turn-off delay (power Down with DLL off)	t_{AOFPD}	2	8,5	2	8,5	ns
RTT dynamic change skew	t_{ADC}	0.3	0.7	0.3	0.7	t_{CK}
Exit self refresh to commands not requiring a locked DLL	t_{XS}	max 5nCK,tR FC + 10ns		max 5nCK,tR FC + 10ns		ns
Write levelling setup from rising CK, CK# crossing to rising DQS, DQS# crossing	t_{WLS}	195		245		ps
Write levelling setup from rising DQS, DQS# crossing to rising CK, CK# crossing	t_{WLH}	195		245		ps
First DQS, DQS# rising edge	t_{WLMRD}	40		40		t_{CK}
DQS, DQS# delay	t_{WLDQSEN}	25		25		t_{CK}

DDR3 SDRAM COMPONENT ELECTRICAL CHARACTERISTICS AND RECOMMENDED AC OPERATING CONDITIONS (Continued)

(0°C ≤ T_{CASE} ≤ + 85°C; V_{DDQ} = +1.5V ± 0.075V, V_{DD} = +1.5V ± 0.075V)

AC CHARACTERISTICS		10600-999		8500-777		
PARAMETER	SYMBOL	MIN	MAX	Min	MAX	Unit
Exit reset from CKE HIGH to a valid command	t _{XPR}	max 5nCK, t _{REFC} + 10ns		max 5nCK, t _{REFC} + 10ns		t _{CK}
Begin power supply ramp to power supplies stable	t _{VDDPR}		200		200	ms
RESET# LOW to power supplies stable	t _{RPS}		200		200	ms
RESET# LOW to I/O and RTT High-Z	t _{IOz}		20		20	ns
Exit precharge power-down to any non-READ command	t _{XP}	max 3nCK, 6ns		max 3nCK, 7.5ns		t _{CK}
CKE minimum high/low time	t _{CKE}	max 3nCK, 5.625ns		max 3nCK, 5.625ns		t _{CK}

Temperature Sensor with Serial Presence-Detect EEPROM



Temperature Sensor with Serial Presence-Detect EEPROM Operating Conditions

Parameter / Condition	Symbol	MIN	MAX	Unit
Supply voltage	V _{DDSPD}	+3	+3.6	V
Supply current: V _{DD} = 3.3V	I _{DD}		+2.0	mA
Input high voltage: Logic 1; SCL, SDA	V _{IH}	+1.45	V _{DDSPD} + 1	V
Input low voltage: Logic 0; SCL, SDA	V _{IL}	-	550	mV
Output low voltage: I _{OUT} = 2.1mA	V _{OL}	-	400	mV
Input current	I _{IN}	-5.0	5.0	µA
Temperature sensing range		TBD	TBD	°C
Temperature sensor accuracy		TBD	TBD	°C

A.C. Characteristics of Temperature Sensor
 $V_{CC} = 3.3\text{ V} \pm 10\%$, $T_A = -40^\circ\text{C}$ to $+125^\circ\text{C}$

Symbol	Parameter / Condition	MIN	MAX	Unit
f _{SCL}	SCL clock frequency	10	400	kHz
t _{BUF}	Bus Free Time Between STOP and START	1300		ns
t _F	SDA fall time		300	ns
t _R	SDA rise time		300	ns
t _{HD:DAT}	Data hold time (accepted for Input Data)	0		ns
	Data Hold Time (guaranteed for Output Data)	300	900	ns
t _{H:STA}	Start condition hold time	600		ns
t _{HIGH}	High Period of SCL	600		ns
t _{LOW}	Low Period of SCL	1300		ns
t _{SU:DAT}	Data setup time	100		ns
t _{SU:STA}	Start condition setup time	600		ns
t _{SU:STO}	Stop condition setup time	600		ns
t _{TIMEOUT}	SMBus SCL Clock Low Timeout	25	35	ms
t _i	Noise Pulse Filtered at SCL and SDA Inputs		100	ns
t _{WR}	Write Cycle Time		5	ms
t _{PU}	Power-up Delay to Valid Temperature Recording		100	ms

Temperature Characteristics of Temperature Sensor
 $V_{CC} = 3.3\text{ V} \pm 10\%$, $T_A = -40^\circ\text{C}$ to $+125^\circ\text{C}$

Parameter	Test Conditions/Comments	MAX	Unit
Temperature Reading Error Class B, JC42.4 compliant	+75°C ≤ T _A ≤ +95°C, active range	±1.0	°C
	+40°C ≤ T _A ≤ +125°C, monitor range	±2.0	°C
	-40°C ≤ T _A ≤ +125°C, sensing range	±3.0	°C
ADC Resolution		12	Bits
Temperature Resolution		0.0625	°C
Conversion Time		100	Ms
Thermal Resistance ¹ θ _{JA}	Junction-to-Ambient (Still Air)	92	°C/W

¹ Power Dissipation is defined as $P_J = (T_J - T_A)/\theta_{JA}$, where T_J is the junction temperature and T_A is the ambient temperature. The thermal resistance value refers to the case of a package being used on a standard 2-layer PCB.

Slave Address Bits of Temperature Sensor

Device	Device Type Identifier				Select Address Signals			R/W#
	b7 ¹	b6	b5	b4	b3	b2	b1	b0
EEPROM	1	0	1	0	A ₂	A ₁	A ₀	R/W#
Temp. Sensor	0	0	1	1	A ₂	A ₁	A ₀	R/W#

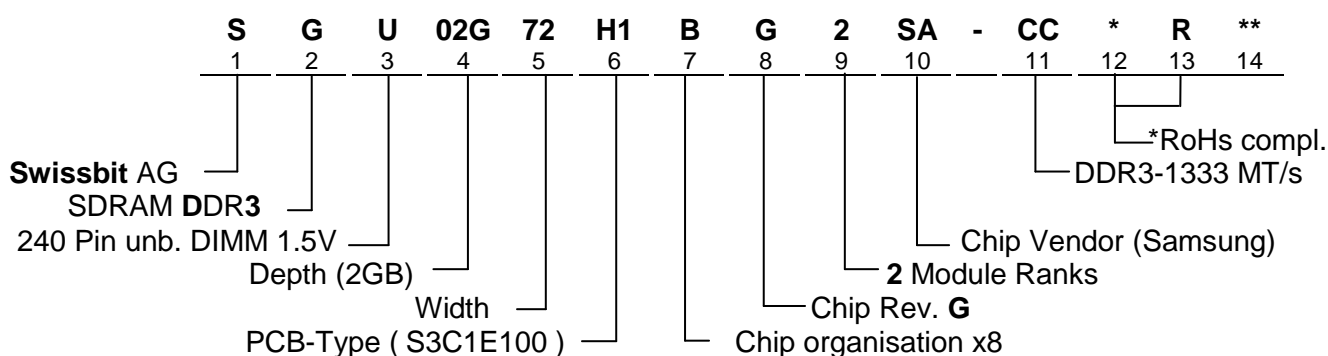
¹ The most significant bit, b7, is sent first.

SERIAL PRESENCE-DETECT MATRIX

Byte	Byte Description	10600-999	8500-777
0	CRC RANGE, EEPROM BYTES, BYTES USED	0x92	
1	SPD REVISION	0x10	
2	DRAM DEVICE TYPE	0x0B	
3	MODULE TYPE (FORM FACTOR)	0x02	
4	SDRAM DEVICE DENSITY & BANKS	0x02	
5	SDRAM DEVICE ROW & COLUMN COUNT	0x11	
6	BYTE 6 RESERVED	0x00	
7	MODULE RANKS & DEVICE DQ COUNT	0x09	
8	ECC TAG & MODULE MEMORY BUS WIDTH	0x0B	
9	FINE TIMEBASE DIVIDEND/DIVISOR	0x52	
10	MEDIUM TIMEBASE DIVIDEND	0x01	
11	MEDIUM TIMEBASE DIVISOR	0x08	
12	MIN SDRAM CYCLE TIME ($t_{CK\ MIN}$)	0x0C	0x0F
13	BYTE 13 RESERVED	0x00	
14	CAS LATENCIES SUPPORTED (CL4 => CL11)	0x3C	0x1C
15	CAS LATENCIES SUPPORTED (CL12 => CL18)	0x00	
16	MIN CAS LATENCY TIME ($t_{AA\ MIN}$)	0x69	
17	MIN WRITE RECOVERY TIME ($t_{WR\ MIN}$)	0x78	
18	MIN RAS# TO CAS# DELAY ($t_{RCD\ MIN}$)	0x69	
19	MIN ROW ACTIVE TO ROW ACTIVE DELAY ($t_{RRD\ MIN}$)	0x30	0x3C
20	MIN ROW PRECHARGE DELAY ($t_{RP\ MIN}$)	0x69	
21	UPPER NIBBLE FOR t_{RAS} & t_{RC}	0x11	
22	MIN ACTIVE TO PRECHARGE DELAY ($t_{RAS\ MIN}$)	0x20	0x2C
23	MIN ACTIVE TO ACTIVE/REFRESH DELAY ($t_{RC\ MIN}$)	0x89	0x95
24	MIN REFRESH RECOVERY DELAY ($t_{RFC\ MIN}$) LSB	0x70	
25	MIN REFRESH RECOVERY DELAY ($t_{RFC\ MIN}$) MSB	0x03	
26	MIN INTERNAL WRITE TO READ CMD DELAY ($t_{WTR\ MIN}$)	0x3C	
27	MIN INTERNAL READ TO PRECHARGE CMD DELAY ($t_{RTP\ MIN}$)	0x3C	
28	MIN FOUR ACTIVE WINDOW DELAY ($t_{FAW\ MIN}$) MSB	0x00	0x01
29	MIN FOUR ACTIVE WINDOW DELAY ($t_{FAW\ MIN}$) LSB	0xF0	0x2C
30	SDRAM DEVICE OUTPUT DRIVERS SUPPORTED	0x83	
31	SDRAM DEVICE THERMAL & REFRESH OPTIONS	0x01	

Byte	Byte Description	10600-999	8500-777
32	MODULE THERMAL SENSOR		0x80
33	SDRAM DEVICE TYPE		0x00
	BYTES 32-59 RESERVED		0x00
60	MODULE HEIGHT (NOMINAL)		0x03
61	MODULE THICKNESS (MAX)		0x11
62	REFERENCE RAW CARD ID		0x04
63	ADDRESS MAPPING EDGE CONECTOR TO DRAM		0x01
64-116	BYTES 64-116 RESEVED		0x00
117	MODULE MFR ID (LSB)		0x83
118	MODULE MFR ID (MSB)		0xDA
119	MODULE MFR LOCATION ID		0x01 (Switzerland) 0x02 (Germany) 0x03 (USA)
120	MODULE MFR YEAR		x
121	MODULE MFR WEEK		x
122-125	MODULE SERIAL NUMBER		x
126-127	CRC	0x346A	0x76C3
128-145	MODULE PART NUMBER	"SGU02G72H1BG2SA-xx"	
146	MODULE DIE REV		0x52
147	MODULE PCB REV		0x54
148	DRAM DEVICE MFR ID (LSB)		0x80
149	DRAM DEVICE MFR (MSB)		0xCE
150-175	MFR RESERVED BYTES 150-175		0xFF
176-255	CUSTOMER RESERVED BYTES 176-255		0xFF

Part Number Code



* optional / additional information

** T = Termal Sensor on Module

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